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FIRST INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Com	mplete if Known	
Application Number	10/743,792	
Filing Date	December 24, 2003	
First Named Inventor	Stefan Schulte et al.	
Examiner Name	Unassigned	
Attorney Docket Number	007413-070	



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Date

Examiner Signature Date Considered 12.70-04
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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Application Number 10/743,792

Filing Date December 24, 2003

First Named Inventor Stefan Schulte et al.

Examiner Name Unassigned 2471

Attorney Docket Number 007413-070

	NON-PATENT LITERATURE DOCUMENTS		
Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journa serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		
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